

Feasibility of T/R Module Functionality in a Single SiGe IC

Dr. John D. Cressler, Jonathan Comeau, Joel Andrews,
Lance Kuo, Matt Morton, and Dr. John Papapolymerou

*Georgia Institute of Technology
Georgia Electronic Design Center*

Mark Mitchell, Tracy Wallace, and Mike Harris,
Georgia Tech Research Institute

Bob Parks and Gisele Wilson,
US Army Space and Missile Defense Command

DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.



Report Documentation Page			Form Approved OMB No. 0704-0188	
<p>Public reporting burden for the collection of information is estimated to average 1 hour per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing this burden, to Washington Headquarters Services, Directorate for Information Operations and Reports, 1215 Jefferson Davis Highway, Suite 1204, Arlington VA 22202-4302. Respondents should be aware that notwithstanding any other provision of law, no person shall be subject to a penalty for failing to comply with a collection of information if it does not display a currently valid OMB control number.</p>				
1. REPORT DATE 01 MAY 2007	2. REPORT TYPE N/A	3. DATES COVERED -		
4. TITLE AND SUBTITLE Feasibility of T/R Module Functionality in a Single SiGe ICF feasibility ICDr			5a. CONTRACT NUMBER	
			5b. GRANT NUMBER	
			5c. PROGRAM ELEMENT NUMBER	
6. AUTHOR(S)			5d. PROJECT NUMBER	
			5e. TASK NUMBER	
			5f. WORK UNIT NUMBER	
7. PERFORMING ORGANIZATION NAME(S) AND ADDRESS(ES) Georgia Institute of Technology			8. PERFORMING ORGANIZATION REPORT NUMBER	
9. SPONSORING/MONITORING AGENCY NAME(S) AND ADDRESS(ES)			10. SPONSOR/MONITOR'S ACRONYM(S)	
			11. SPONSOR/MONITOR'S REPORT NUMBER(S)	
12. DISTRIBUTION/AVAILABILITY STATEMENT Approved for public release, distribution unlimited				
13. SUPPLEMENTARY NOTES See also ADM202171., The original document contains color images.				
14. ABSTRACT				
15. SUBJECT TERMS				
16. SECURITY CLASSIFICATION OF: a. REPORT b. ABSTRACT c. THIS PAGE unclassified unclassified unclassified			17. LIMITATION OF ABSTRACT UU	18. NUMBER OF PAGES 24
			19a. NAME OF RESPONSIBLE PERSON	

SiGe Single-Chip T/R Program

1990's

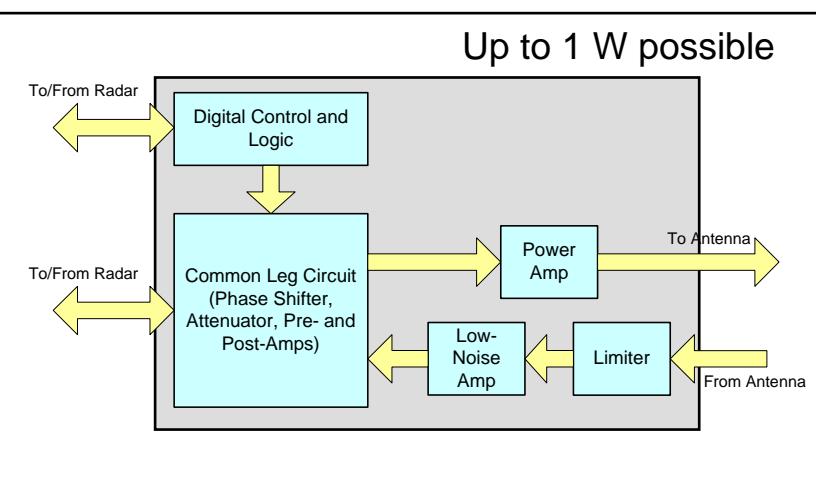
- ♦ Multi-chip module
- ♦ Expensive (~ \$1000)
- ♦ High power
- ♦ Cost drivers:
 - ♦ MMIC area
 - ♦ Touch labor
 - ♦ Packaging



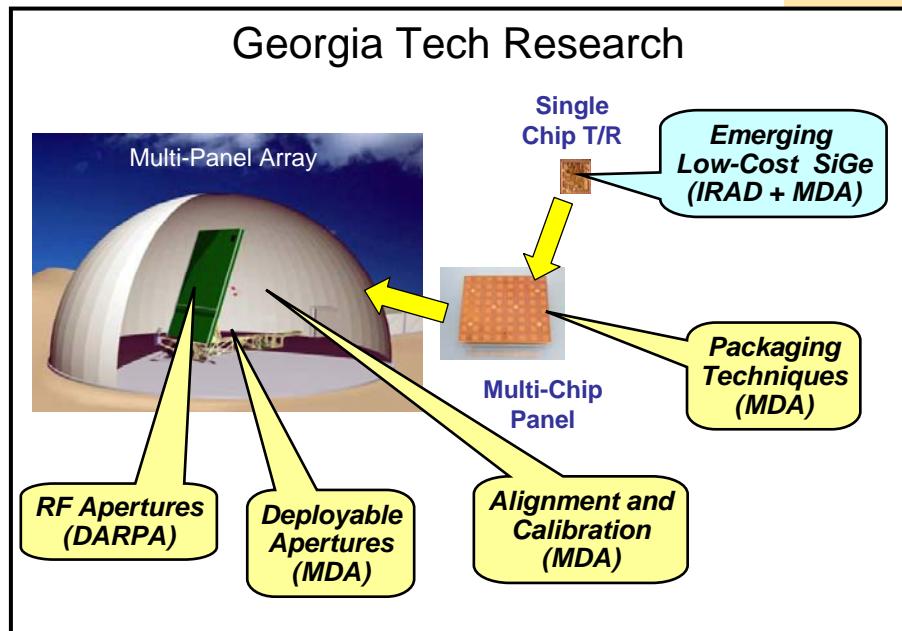
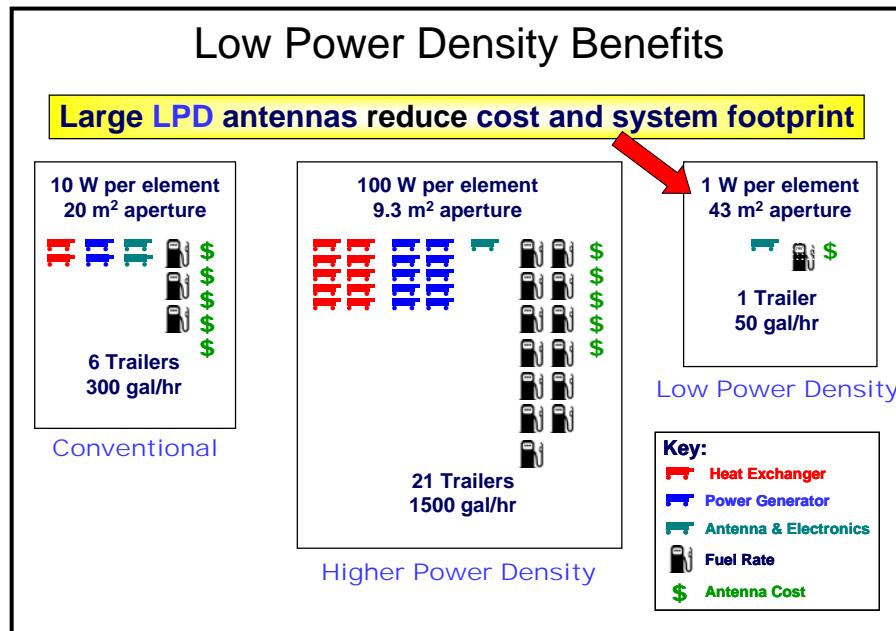
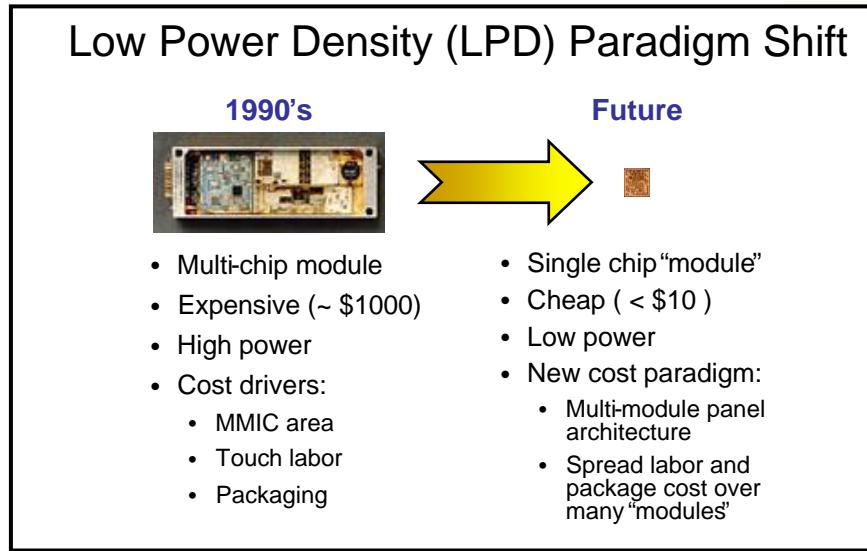
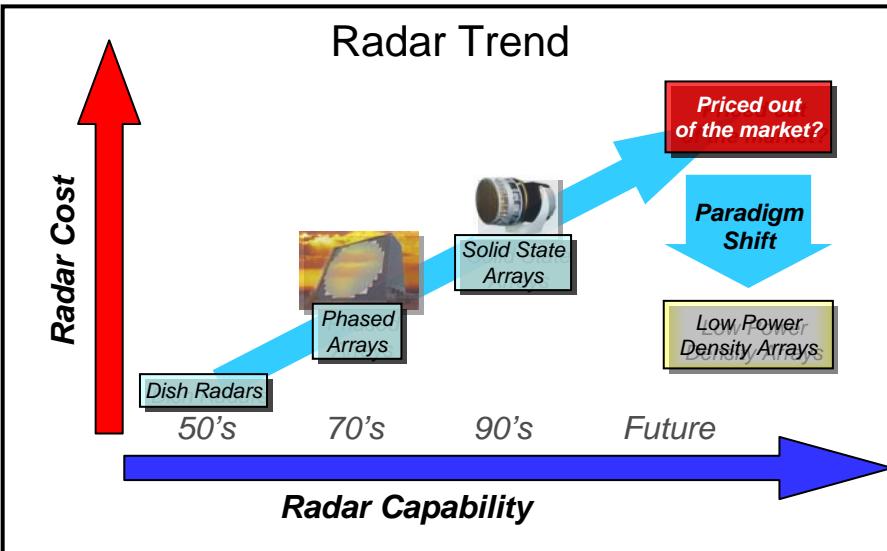
- ♦ GTRI and GEDC co-development
- ♦ Full Transmit/Receive module functionality in a single chip
- ♦ Currently developing devices
- ♦ Integrated chips to be available in FY07

Future

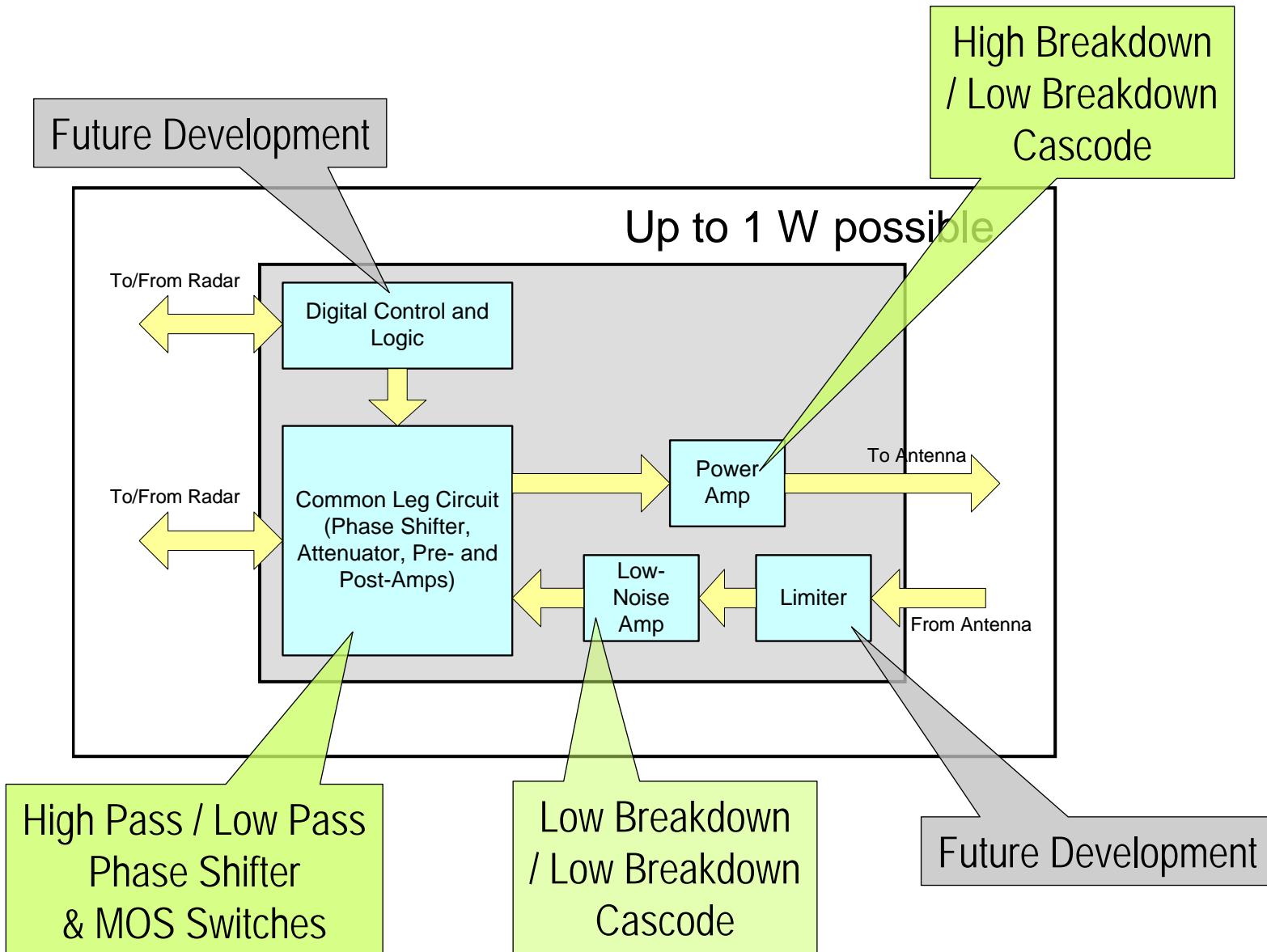
- ♦ Single chip "module"
- ♦ Cheap (< \$10)
- ♦ Low power
- ♦ New cost paradigm:
 - ♦ Multi-chip panel architecture
 - ♦ Spread labor and package cost over many "modules"



Redefining Future Radar Technology

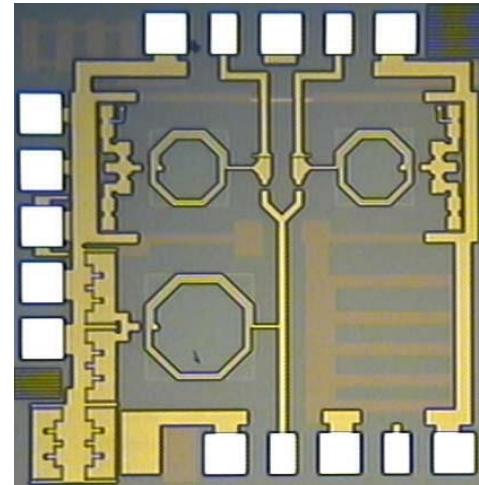


SiGe T/R Chip Development



Accomplishments to Date

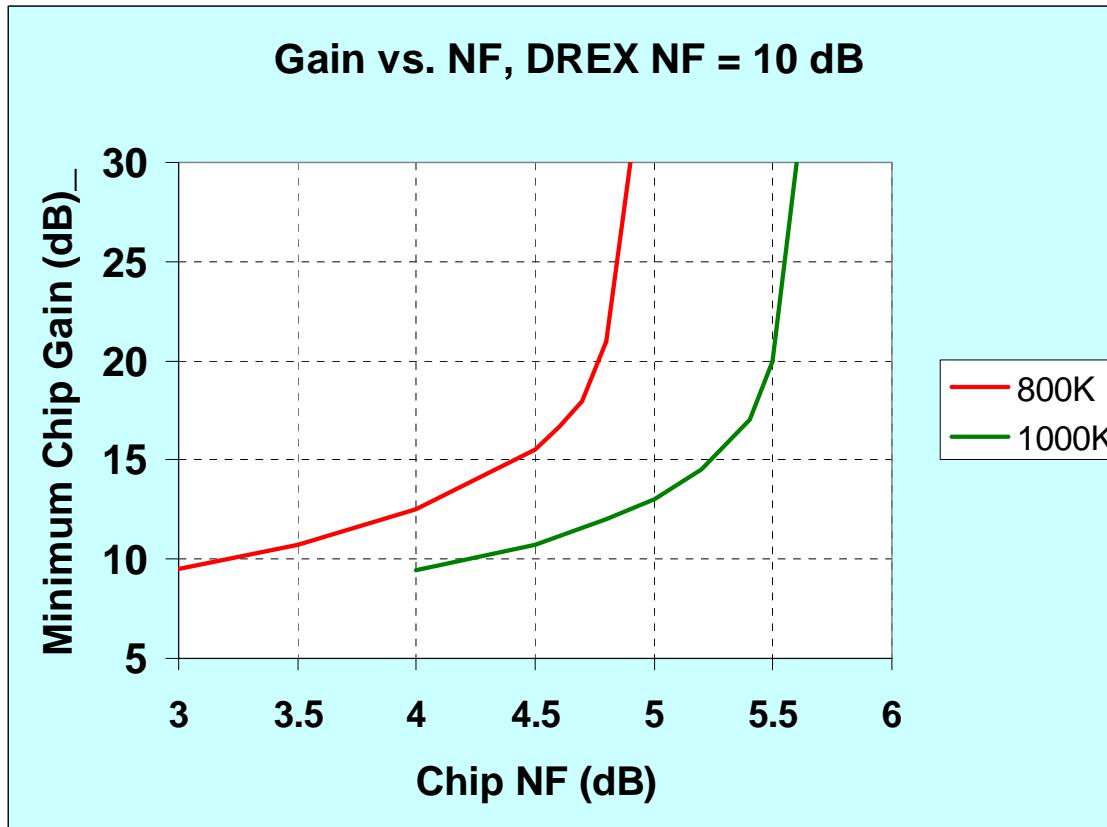
- ✓ Developed detailed T/R chip requirements
- ✓ Developed preliminary design
- ✓ Reviewed and Analyzed preliminary design
- ✓ Trade off design, specifications, and performance
- ✓ Designed and fabricated critical components
- ✓ Tested components



Gain / Noise Figure Requirements

◆ Requirements based on:

- ◆ Overall system noise temperature of 800K (Objective) 1000K (Threshold)
- ◆ Assumed Digital Receiver/Exciter (DREX) input NF = 10 dB



Phase Shifter Bit Requirements

At least 4 bits required for negligible gain loss

Number of Bits, N	Gain Loss (dB)
2	-1.000
3	-0.229
4	-0.056
5	-0.014
6	-0.003

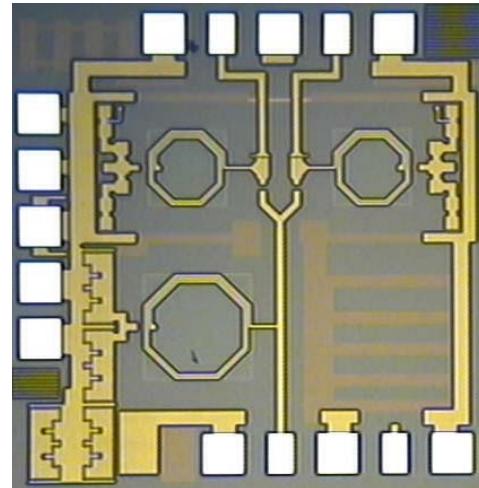
Increase to 5 bits preferable for low sidelobe performance

Number of bits	Minimum bit size (degrees)	RMS Phase Error (degrees)
2	90	26.0
3	45	13.0
4	22.5	6.5
5	11.25	3.2
6	5.625	1.6
7	2.8125	0.8

4-bit threshold and 5-bit objective requirements selected

Component Results to Date

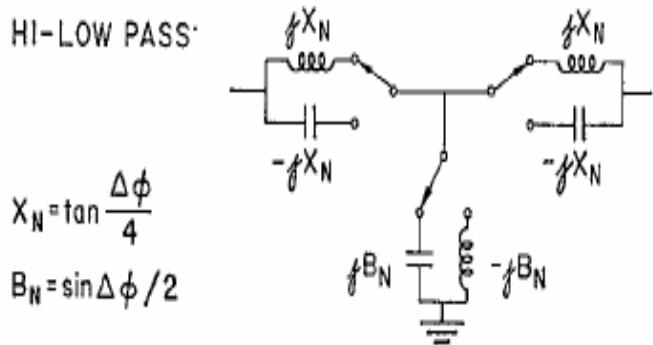
- ✓ Hi Pass / Lo Pass Phase Shifter
- ✓ MOS Switches
- ✓ Cascode LNA
- ✓ Cascode Pre Amp
- ✓ Cascode Power Amp



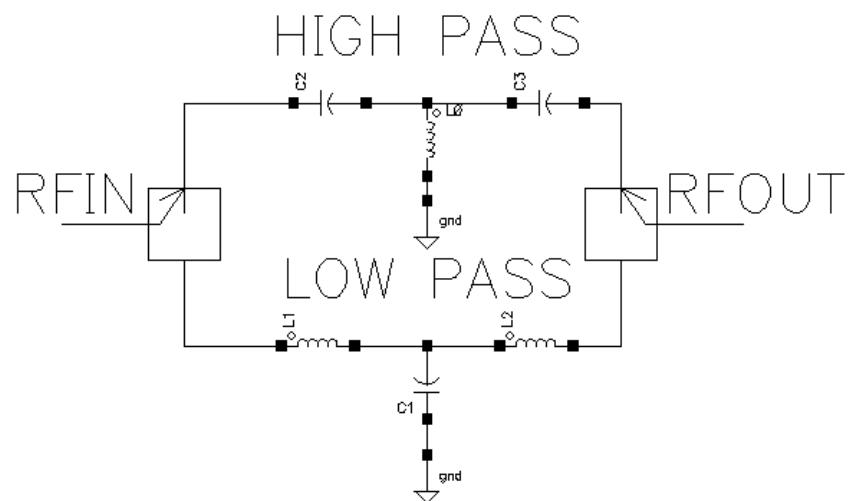
Hi-Low Pass Shifter

- Hi-Low pass phase shifter provides flat phase response
- Shift is relative phase between low pass and high pass
- Very broadband and easier to control than reflection shifter
- Higher values of shift require more elements
- Switch and filter sections can be designed independently
(if filter and switch S11 < -20 dB)

Hi-Low Pass Schematic

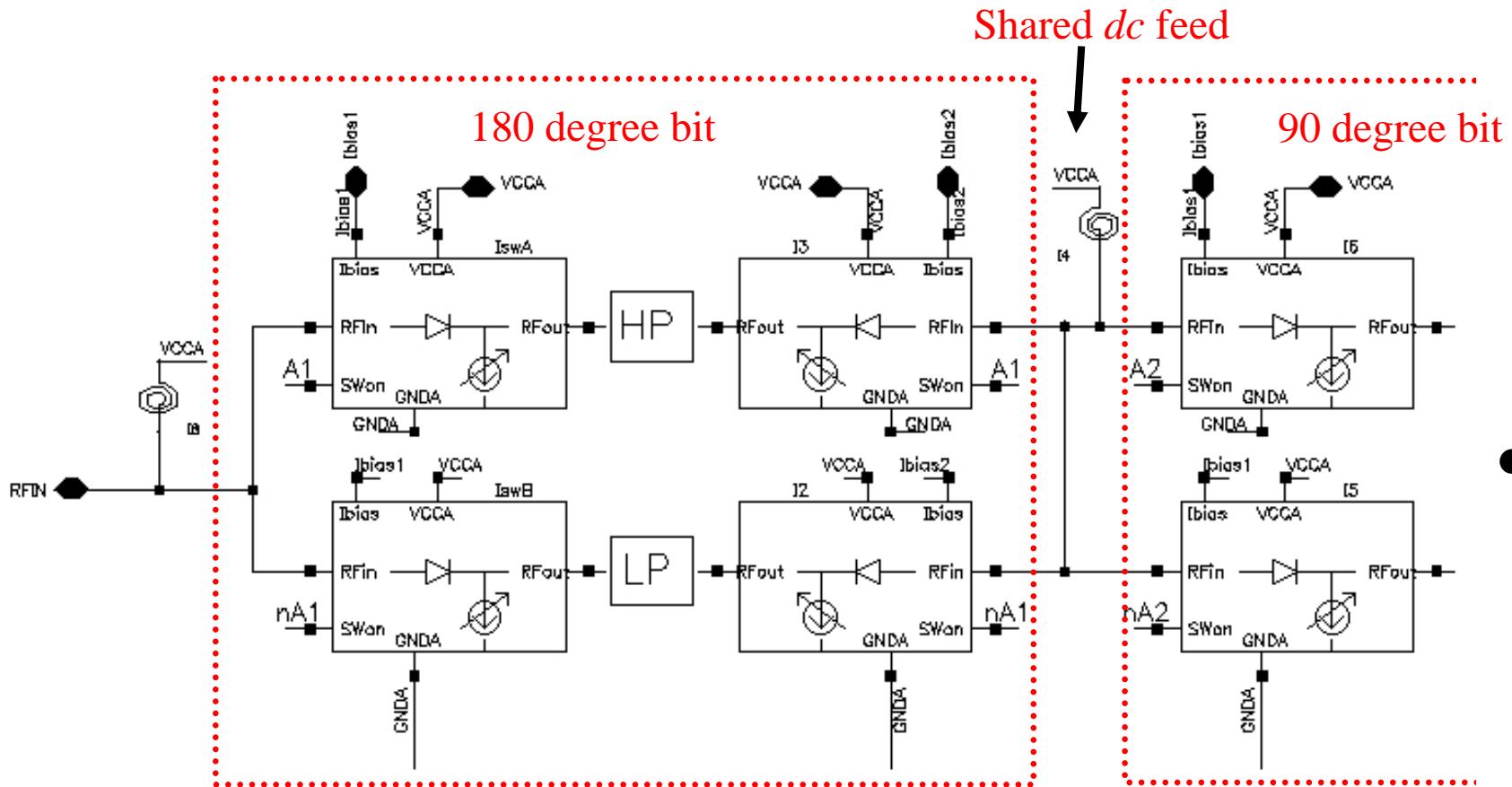


Alternative Topology



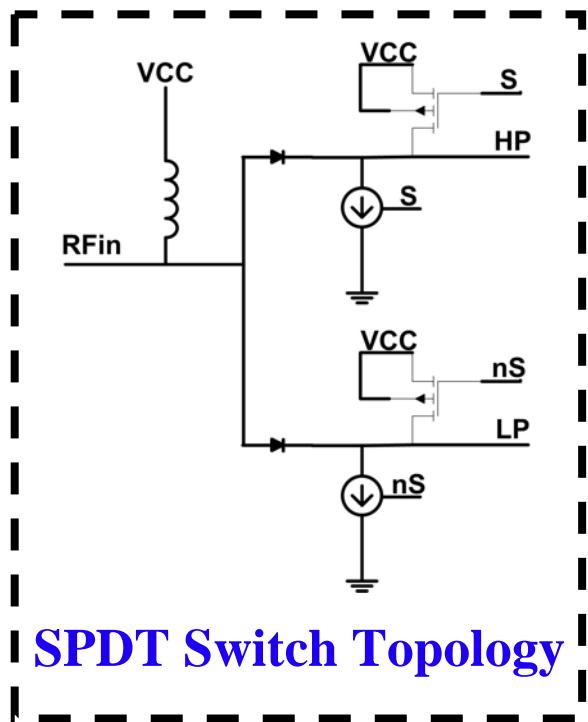
N-bit Hi-Low Pass Shifter

- Bits may be chained together if well matched
- Mismatched bits cause large phase error
- dc feeds shared in between bits



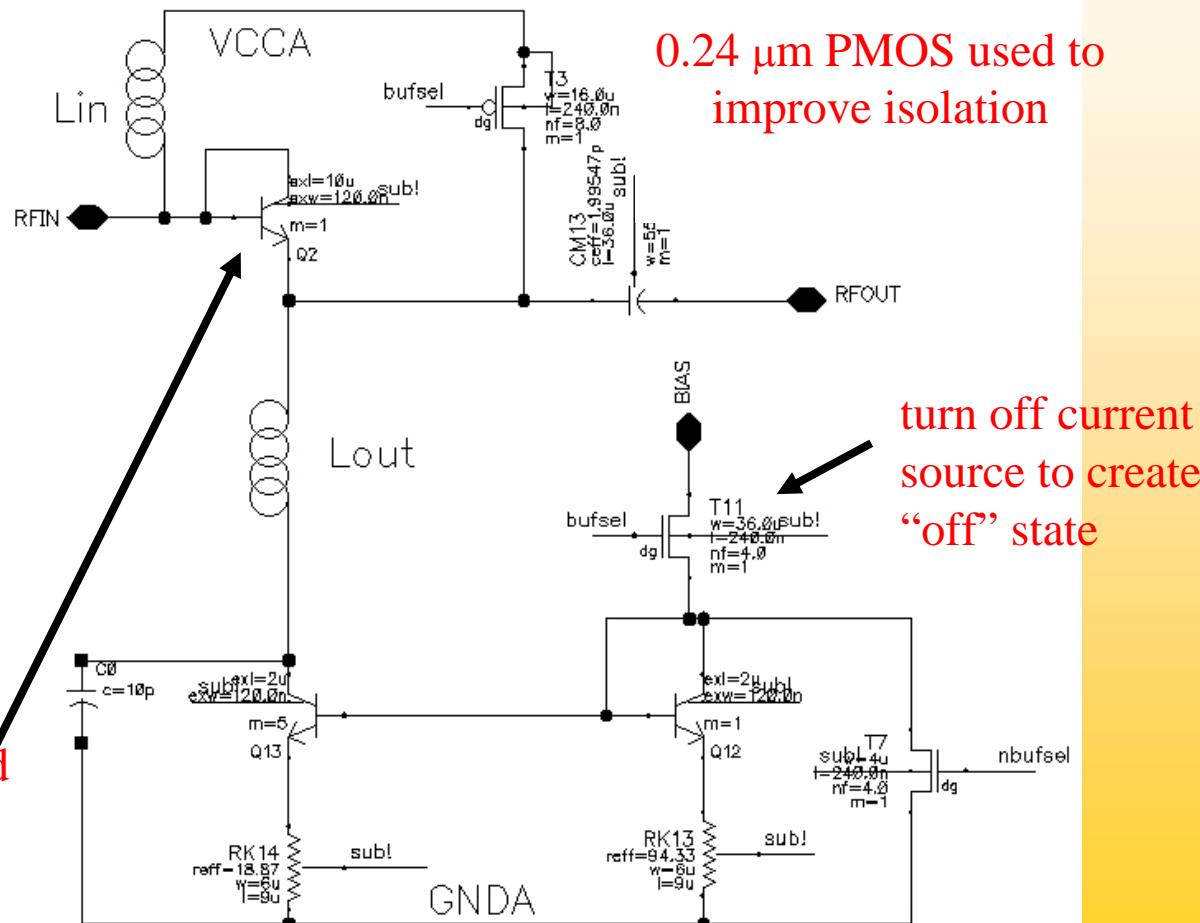
Diode Switch Design

- Series Connected HBT Diode Element for SPDT Switch



SPDT Switch Topology

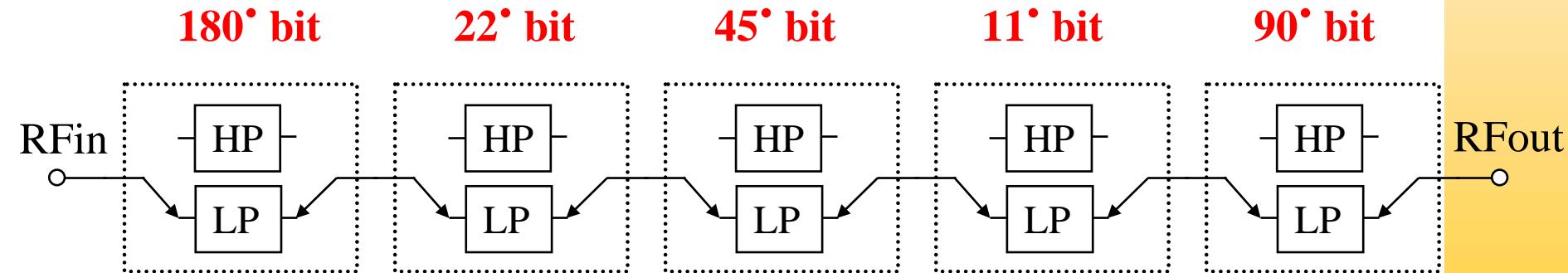
use of diode connected
HBT npn instead of
schottky or PIN diode



Bit Ordering



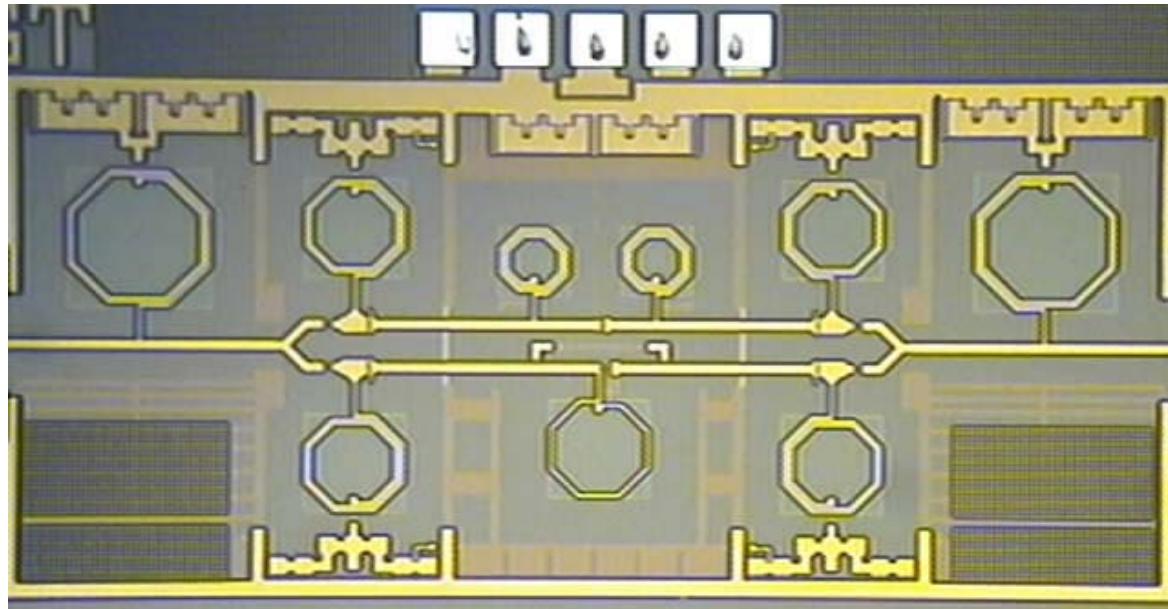
- Higher shift value bits are easily matched ($S_{11} < -25$ dB)
- Smaller bits require smaller element values on low pass
 - Parasitics cause unpredictable shift and impedance match
 - Bits can be optimized with higher values at cost of match
- Best performance when poorly matched bits are separated
- Our best bit order is: $180^\circ - 22^\circ - 45^\circ - 11^\circ - 90^\circ$



Preliminary Results

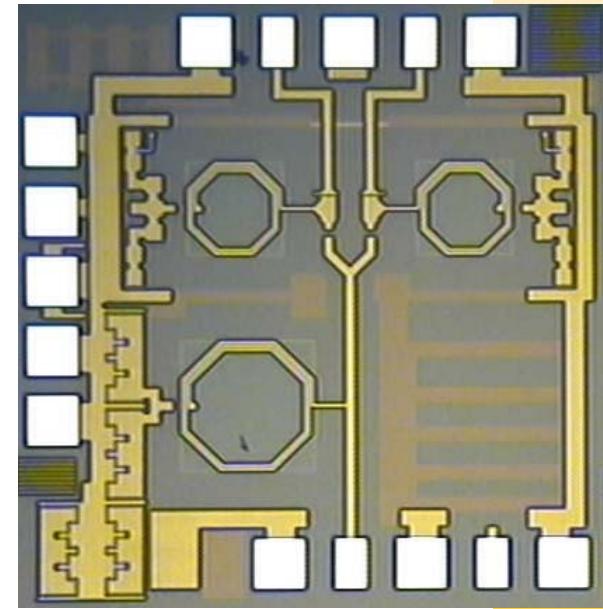
- 90° Section of Shifter and SPDT HBT Switch Fabricated
- Hardware from Jan 05 Tapeout
- Preliminary Designs

90° Section of Shifter



2.56 x 1.2 mm²

SPDT HBT Switch

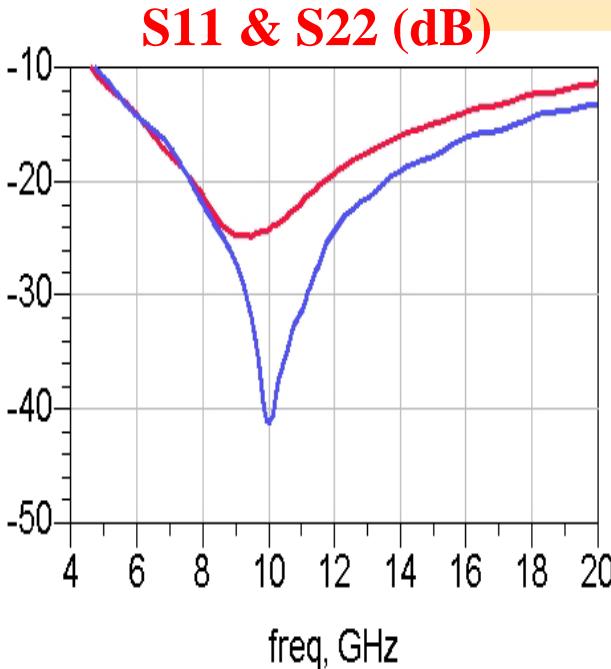
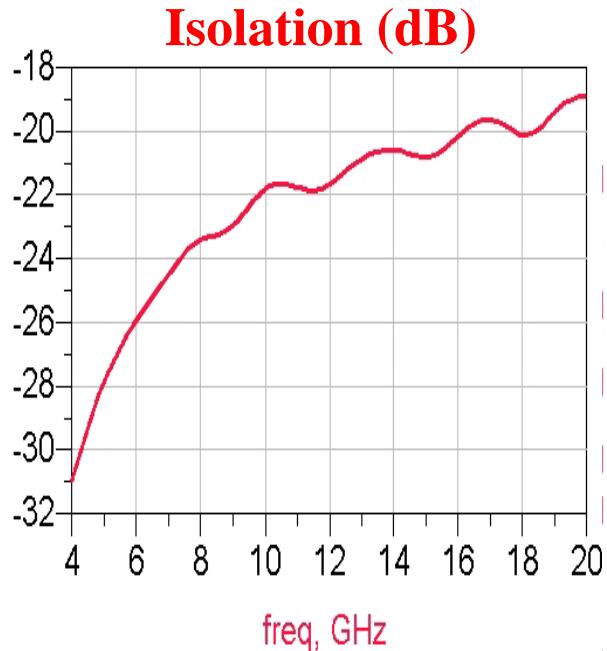
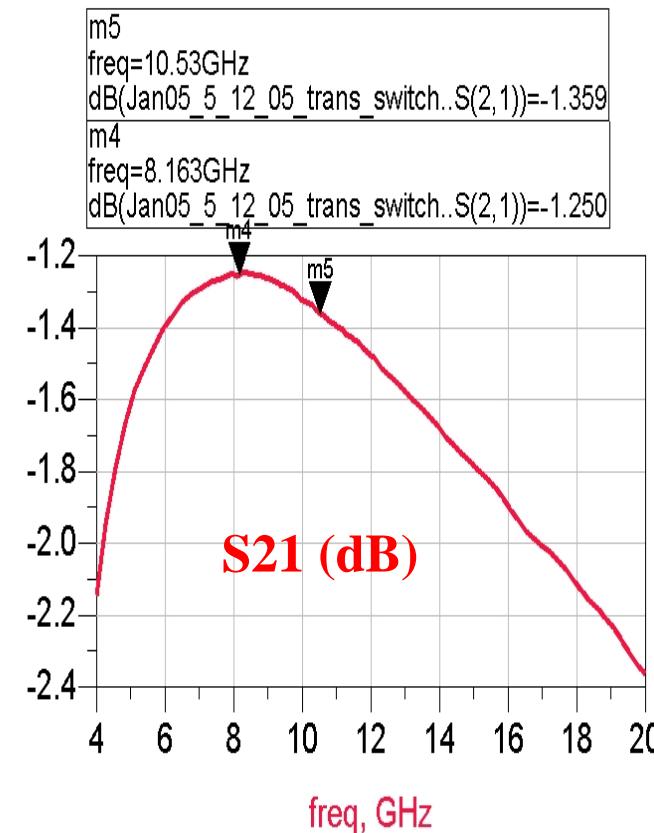


1.2 x 1.2 mm²

Preliminary Results

- Single HBT Diode NPN Switch Fabricated and Tested
- Sim Results: $IL < 0.92 \text{ dB}$, $RL > 19 \text{ dB}$, $I_{SO} > 20 \text{ dB}$, $IIP3 = 24 \text{ dBm}$

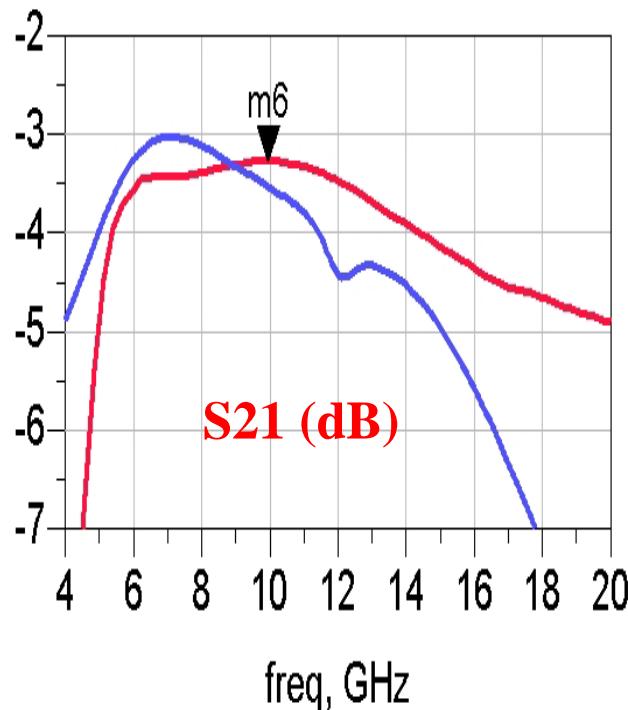
dc: V_{cc}=2.1V, I_{bias} = 1.8mA, I_{cc} = 8.75 mA
Measured IIP3 ~ 20 dBm
Measured IP_{1dB} ~ 3 dBm



Preliminary Results

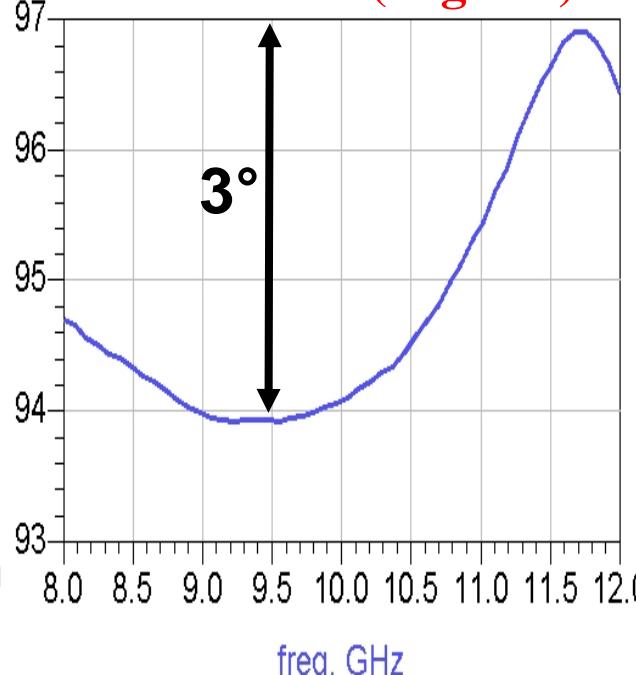
- 90° Section of Shifter Fabricated & Tested
- Sim. Results: IL = 2.1 dB, RL > 15, Phase Shift = 90° +/- 3°

m6
freq=9.959GHz
dB(Jan05_5_12_05_2vbias_shifter..S(2,1))=-3.281

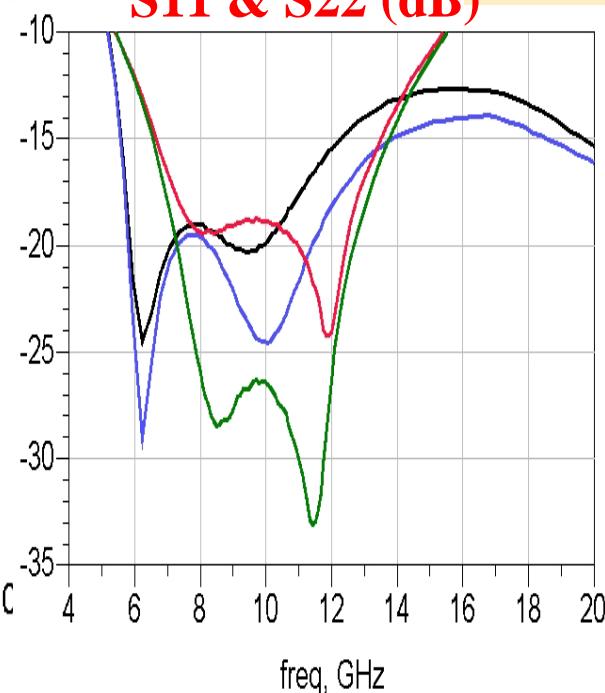


dc: V_{cc}=2.1V, I_{bias1} = I_{bias2} = 1.8mA,
I_{cc} = 17.4 mA

Phase Shift (degrees)

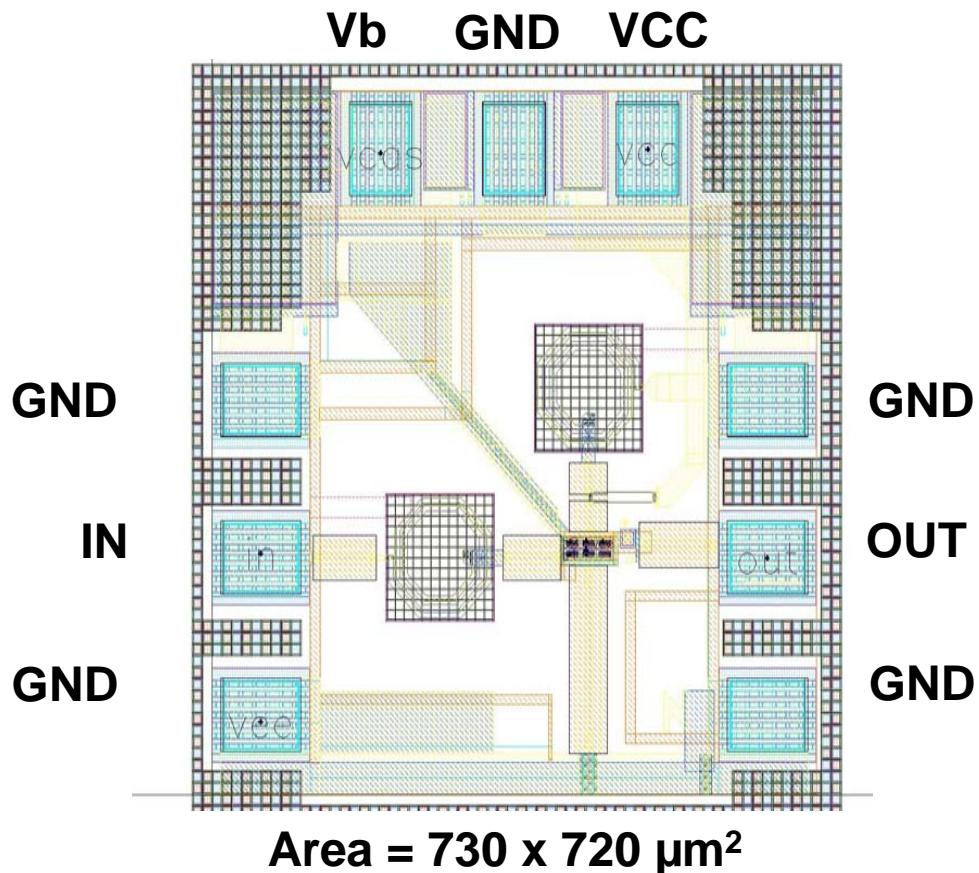


S11 & S22 (dB)



SiGe LNA

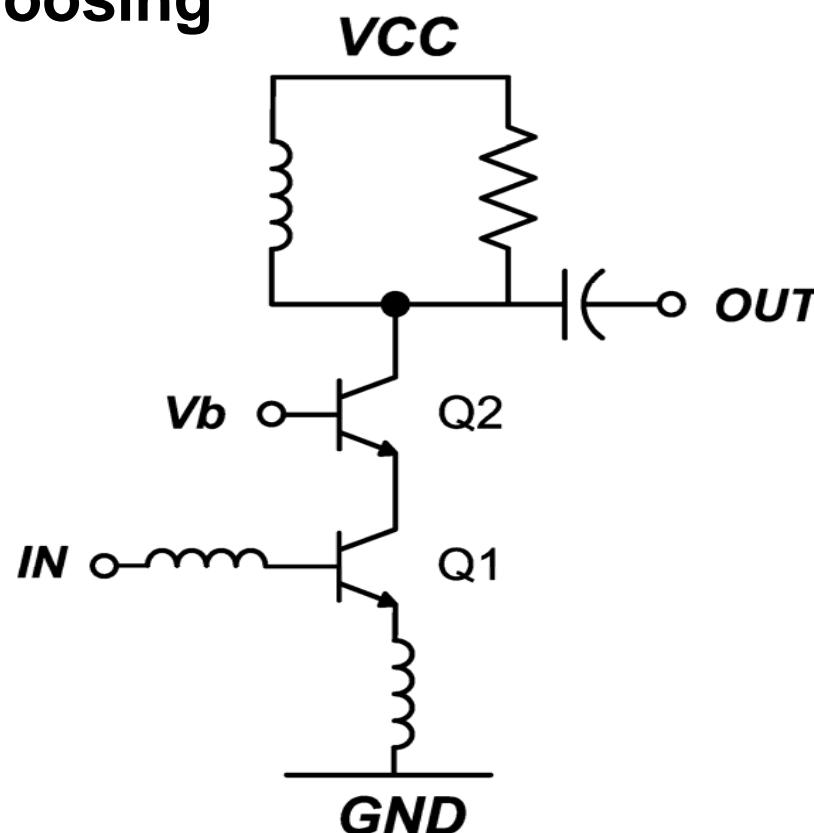
- Layout and bias conditions



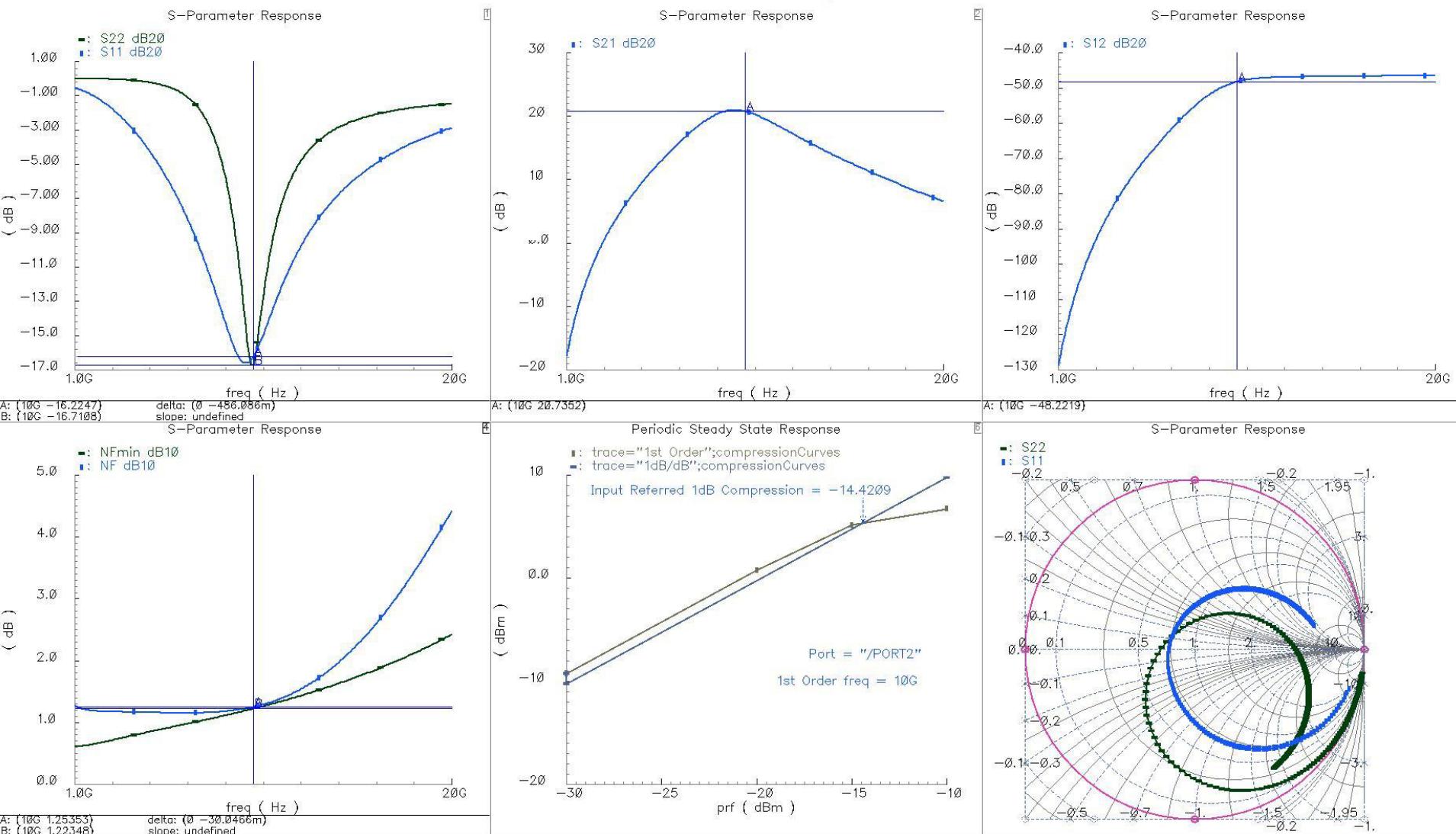
V _{CC}	2.5 V
V _b	2 V
GND	0 V
I _b	14 μA
I _c	6 mA

SiGe LNA

- Cascode topology
 - suppresses feedback and improves stability
- Noise and impedance match by choosing
 - emitter length
 - collector current
 - base inductor
 - emitter inductor
- NF/gain/IIP3 tradeoff



SiGe LNA

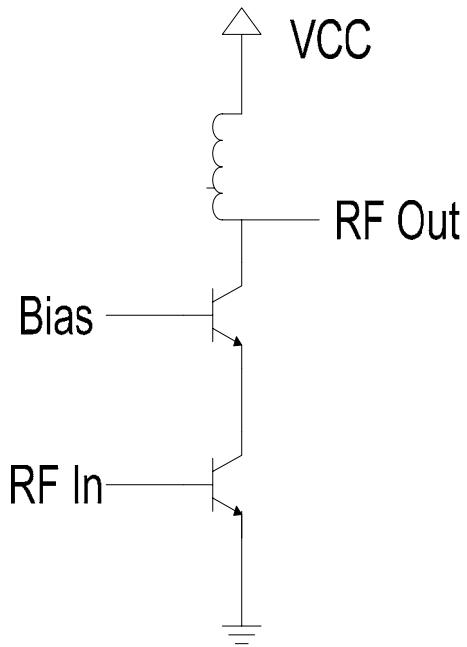
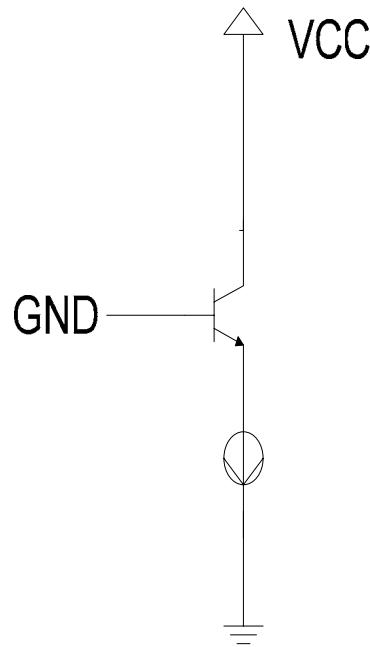


SiGe LNA

- Simulated performance summary

Frequency	10 GHz
S11	< -16 dB
S22	< -16 dB
S21	> 20 dB
NF	< 1.3 dB
Input P1dB	> -15 dBm

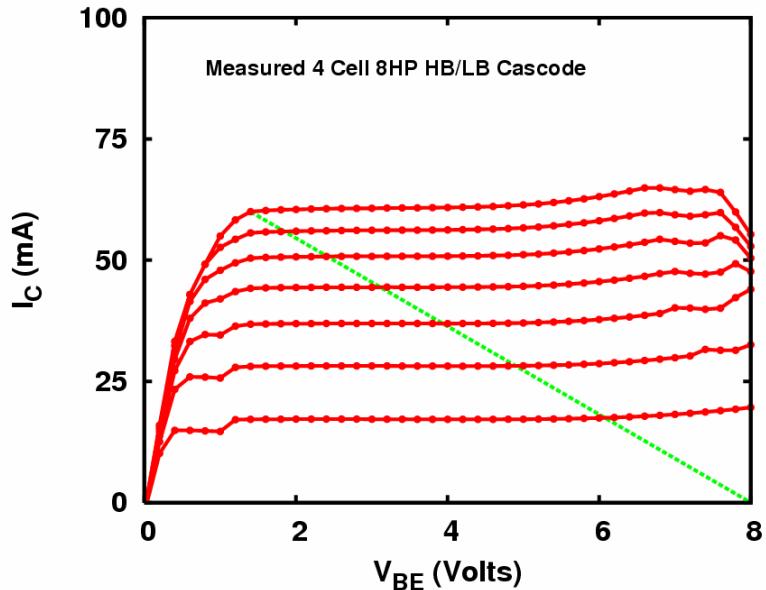
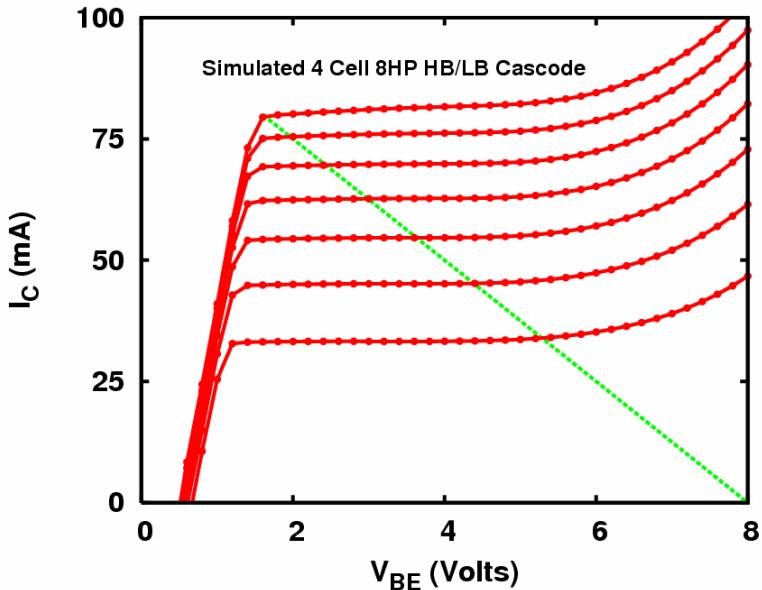
Extend PA Voltage Range



- **Forced Emitter Current**
- **Breakdown Approaches BVCBO**
- **Improves DCIV Linearity**

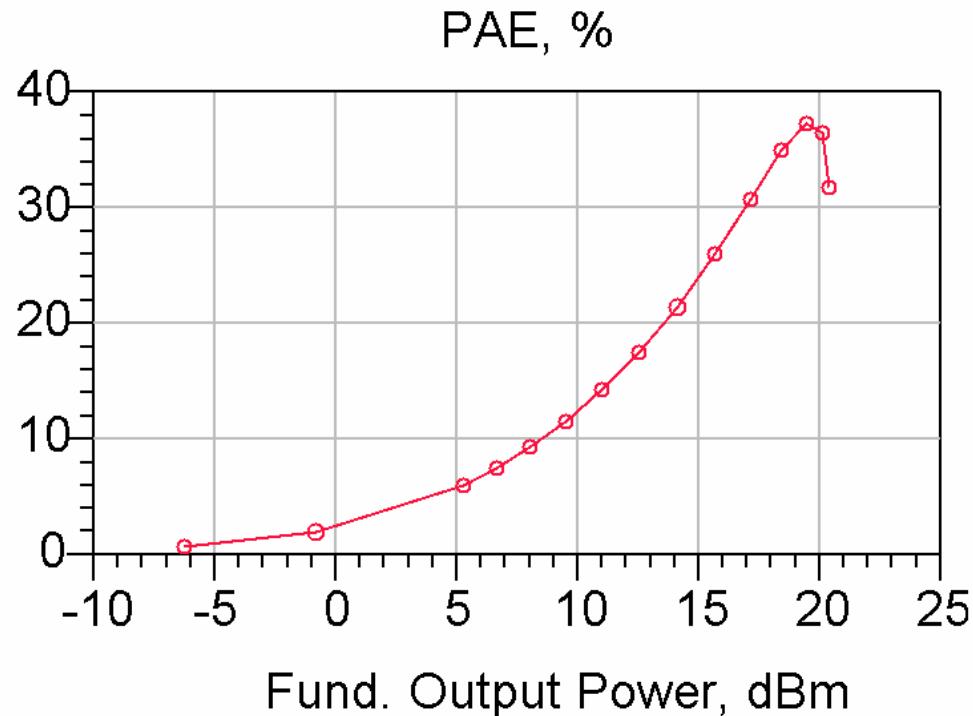
- **Circuit Realization of Forced I_E**
- **Upper bias is AC ground**
- **RF input on lower base**

Cascode PA Characteristics



- Simulated vs. Measured 4 Cell 8HP 0.12x18 HB / 0.12x5 LB
- Slight Beta difference between model and simulation
- Beta compression and breakdown characteristics similar
- Knee voltage equal to $V_{BE} + V_{CESat}$

Simulated Results



8HP Cascoded Devices

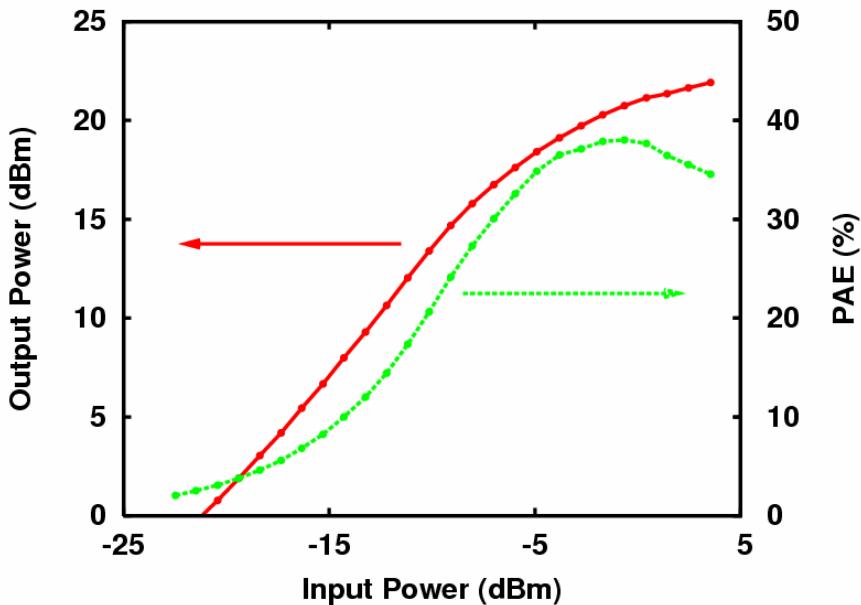
- 12 parallel load pull cells
- Post layout extraction
- Realistic on chip Qs
- Non-optimized for harmonics

Strong Class AB Results

- 19 dBm output power
- 25 dB of gain
- 38% PAE

- **Interconnects modeled using T-line models**
 - Show .1 dB of loss for 500 um run of 40 um wide line

Preliminary PA Results



- **8HP Cascoded Devices**
 - 12 parallel load pull cells
 - Non-optimized for harmonics and layout
 - Slightly mismatched source
- **Strong Class AB Results**
 - 21 dBm output power
 - 20 dB of gain
 - 38% PAE
- **Meets power spec, promising efficiency for pre-driver**
- **~150 total cascode cells to reach 30 dBm with margin for passive losses**

Summary

- ◆ MDA/AS Radar System Technology panel investing in SiGe RF devices for future radar needs
- ◆ SiGe single-chip T/R program
 - ◆ 4-year development plan (FY05-FY08)
 - ◆ First integrated T/R chips in FY07
 - ◆ Requirements developed (FY05)
 - ◆ Critical devices designed and analyzed (FY05)
 - ◆ Some devices fabricated and tested (FY05)
 - ◆ More fabrication runs underway (due back late FY05)
 - ◆ Critical risk reduction for low power density apertures
- ◆ *SiGe Single-chip T/R for Radar appears feasible*

